

XRF

Principle

XRF (X-ray fluorescence) is a non-destructive analytical technique used to determine the elemental composition of materials. XRF analyzers determine the chemistry of a sample by measuring the fluorescent (or secondary) X-ray emitted from a sample when it is excited by a primary X-ray source. Each of the elements present in a sample produces a set of characteristic fluorescent X-rays

Unsuitable for analysis of very light elements e.g. H to B

Capabilities

- Elementary Analysis

Assets

	Asset	Details
	Malvern Panalytical Zetium	WD-XRF spectrometer for Elemental Analysis

[back to Inorganic Lab](#)
[Home](#)